SDM23003-30H



Product Features

- 2300~2400MHz
- 44.7W Saturated Power @ 48V
- 13% Drain Efficiency @ 31dBm
- Internally 50ohm Matched
- 2-Stage Amplifier Module
- GaN on SiC Technology

Applications

- Massive MIMO
- 4G System
- Multi-Band, Multi-Mode
- Multi-Carrier
- RRH Drive Amplifier





Package Type: PP-3G

Description

The SDM23003-30H is a fully integrated micro-strip GaN Hybrid power amplifier module designed for applications in 4G LTE MIMO systems, small cells and low power remote radio heads. SDM Series is an integrated 2-stage power amplifier module, 50ohm input and output impedance matched device can deliver up to 44.7W of saturation power and operating drain voltage 48V. This device is size 8x14x2.6mm and is packaged in a ceramic surface mount package.

Typical Performance

 $(V_{DS} = +48V, T_{C} = 25^{\circ}C, 50\Omega)$

Fraguency [MHz]	Peak Output Power		Average	e Power*1	
Frequency [MHz]	Power [W]	Power [W]	Gain [dB]	Drain Efficiency [%]	ACLR [dBc]
2310	50.9	1.3	43.3	12.6	-41.9
2350	50.2	1.3	43.6	12.7	-41.6
2390	48.9	1.3	43.9	12.8	-41.8

Note

Absolute Maximum Ratings

Rating	Symbol	Value	Unit	Condition
Drain to Source Voltage	V _{DSS}	100	V	Tc=25 °C
Gate to Source Voltage	V_{GS}	-10, +2	V	Tc=25 °C
Operating Voltage	V_{DD}	52	V _{DC}	
Storage Temperature	T_{STG}	-40, +125	°C	
Case Operating Temperature	$T_{\rm C}$	-30, +125	°C	
Operating Junction Temperature*1	T_{J}	225	°C	
Soldering Temperature*2	T_{S}	250	°C	

Note

^{*1} Measured in the SDM23003-30H test board amplifier circuit, under LTE 20MHz 1carrier, PAR 7.5dB @0.01% probability on CCDF.

^{*1} Continuous use at maximum temperature will affect MTTF.

 $^{*2\} Refer to the\ Application\ Note (AN-002)\ on\ soldering\ -\ "Solder\ Condition\ for\ RFHIC's\ GaN\ Device"$



Electrical Characteristics*1 (T_C=25°C unless otherwise noted)

Characteristics	Conditions	Symbol	Min	Тур	Max	Unit
	DC C	Characteristics (Main)			
Maximum Forward Gate Current	Tc= 25 ℃	I_{GMAX}	-	-	5	mA
Maximum Drain Current*2	Tc= 25 ℃	I_{DMAX}	-	-	3.2	A
Power Dissipation	Tc= 85 ℃	P_{DMAX}	-	-	29.8	W
Gate Threshold Voltage	$V_{DS} = 10V$ $I_{D} = 5.2mA$	$V_{\rm GS(TH)}$	-3.8	-3.0	-2.3	V_{DC}
Gate Quiescent Voltage	$V_{DS} = 48V$ $I_{D} = 60mA$	$V_{\mathrm{GS(Q)}}$	-3.7	-2.9	-2.2	V _{DC}
Drain-Source Breakdown Voltage	$V_{GS} = -8V$ $I_{D} = 5.2mA$	V _{BR}	150	-	-	V
Saturated Drain Current*3	$V_{DS} = 6V$ $V_{GS} = 2V$	I_{DS}	4.2	5.2	-	A
Gate Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	$I_{GLKG150}$	-1.6	-	-	mA
Drain Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	$I_{ m DLKG150}$	-	-	2.1	mA
	DC C	haracteristics (Drive)			
Maximum Forward Gate Current	Tc= 25 ℃	I_{GMAX}	-	_	1	mA
Maximum Drain Current*2	Tc= 25℃	I_{DMAX}	-	-	0.3	A
Power Dissipation	Tc= 85 ℃	P_{DMAX}	-	_	12.2	W
Gate Threshold Voltage	$V_{DS} = 10V$ $I_{D} = 0.52mA$	$V_{GS(TH)}$	-3.8	-3.0	-2.3	V_{DC}
Gate Quiescent Voltage	$V_{DS} = 48V$ $I_{D} = 30mA$	$V_{GS(Q)}$	-3.7	-2.7	-2.2	V_{DC}
Drain-Source Breakdown Voltage	$V_{GS} = -8V$ $I_{D} = 0.52mA$	V_{BR}	0	-	-	V
Saturated Drain Current*3	$V_{DS} = 6V$ $V_{GS} = 2V$	I_{DS}	0.4	0.5	-	A
Gate Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	$I_{GLKG150}$	-0.2	-	-	mA
Drain Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	$I_{ m DLKG150}$	-	-	0.2	mA

Note

^{*1} Measured on wafer prior to packaging.

^{*2} Current Limit for long term, reliable operation

^{*3} Scaled from PCM data.

GaN Hybrid PAM

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Characteristics	Conditions	Symbol	Min	Тур	Max	Unit	
	RF Characteristics (F=2350MHz unless otherwise noted)						
Saturated Output Power*1, 4	$V_{DS} = 48V$	P _{SAT}	35.5	44.7	56	W	
Modulated Gain*2	$V_{DS} = 48V$	G_{P}	38	43	48	dB	
Modulated Gain	$P_{OUT} = 31dBm$	- r			.0	u2	
Linearity*2	$V_{DS} = 48V$	ACLR	-50	-40	-30	dBc	
Linearity	$P_{OUT} = 31dBm$	Hezk	30		30	uBe	
Modulated Drain Efficiency*2	$V_{DS} = 48V$		11	13	15	%	
Wiodulated Drain Efficiency	$P_{OUT} = 31dBm$	η	11	13	13	70	
Output Mismatch Stress*1,3	$V_{DS} = 48V$	VSWR	_	_	10:1	W	
	$P_{OUT} = P_{SAT}$ Pulsed	VOWK	_	-	10.1	Ψ	

Note

^{*1} Pulse width 10 μ sec, Pulse period 100 μ sec.

 $^{^*2}$ Measured in the SDM23003-30H test board amplifier circuit, under LTE 20MHz 1carrier, PAR 7.5dB @0.01% probability on CCDF. Drive Idq=30mA, Main Idq=60mA

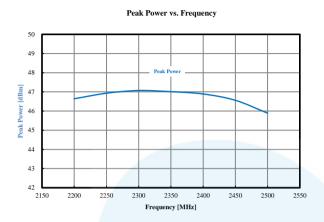
^{*3} Measured in the SDM23003-30H test board amplifier circuit. No damage at all phase angles.

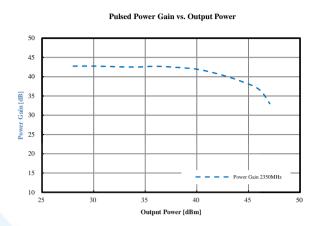
^{*4} Psat is defined as ΔPout/ΔPin<0.1, where ΔPin is increased input power, ΔPout is increased output power.



Typical Pulsed Signal Performance

(Tc=25°C, Measured in the SDM23003-30H test board amplifier circuit)

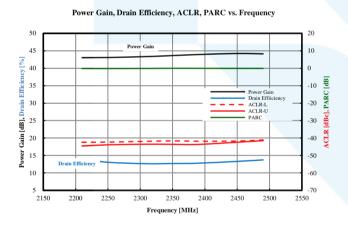




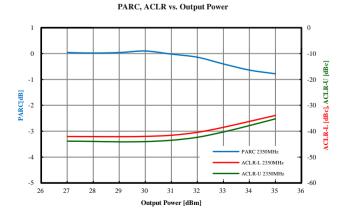
Pulse width 10µsec, Pulse period 100µsec.

Typical Modulated Signal Performance

(Tc=25°C, Measured in the SDM23003-30H test board amplifier circuit)





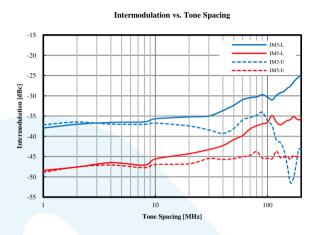


 $P_{AVG} = 31 dBm, \qquad V_{DS} = 48V, \qquad Drive\ Idq = 30 mA, \quad Main\ Idq = 60 mA$ $LTE\ 20 MHz\ 1 carrier, PAR\ 7.5 dB\ @0.01\%\ probability\ on\ CCDF.$



Typical 2-tone Intermodulation Imbalance Performance

(Tc=25°C, Measured in the SDM23003-30H test board amplifier circuit)



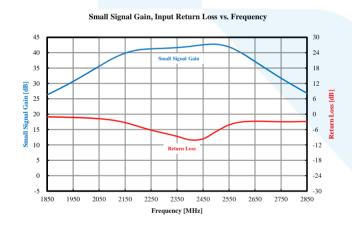
2-tone Power = 31dBm,

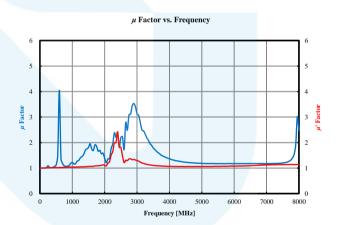
 $V_{DS} = 48V$,

Drive Idq=30mA, Main Idq=60mA

Typical Small Signal Performance

(Tc=25°C, Measured in the SDM23003-30H test board amplifier circuit)



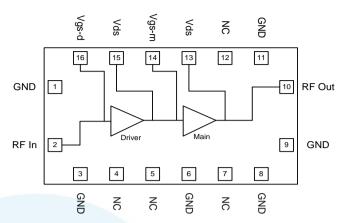


Input Power= -30dBm, $V_{DS} = 48V$,

Drive Idq=30mA, Main Idq=60mA

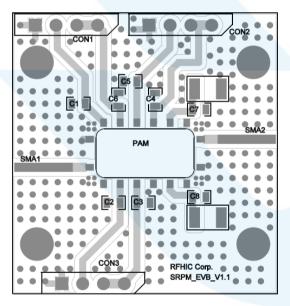


Block Diagram



- * Gate Pin assignment Vgs-d (Driver Gate)
- Vgs-m (Main Gate)

Test Board Component Layout

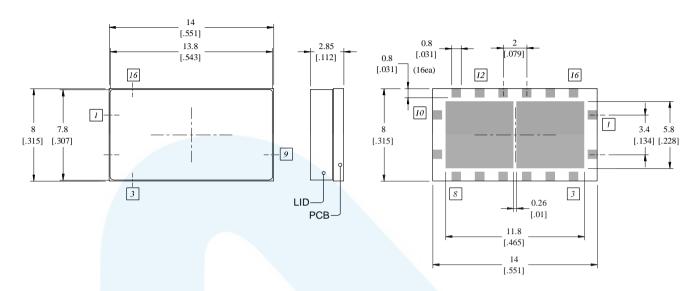


Part	Description Part Number		Manufacturer
C3, C4, C6, C7, C8	C7, C8 1.0uF / 100V GRM21BC72A105KE01		MURATA
C1, C2, C5	4.7uF / 16V	GRM21BR71C475KE51L	MURATA
PCB	2Layer, 20mil, 1oz	RO4350B	ROGERS
CON1~3	2.54mm Male Connector	5267-04A	MOLEX
SMA1~2	Female Connector	-	-
PAM	GaN Hybrid PAM	SDM23003-30H	RFHIC



Package Dimensions (Type:PP-3G)

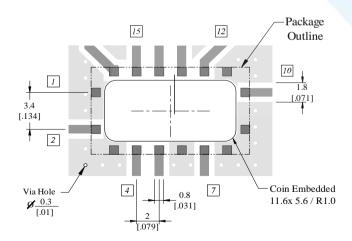
* Unit: mm[inch] | Tolerance: ±0.15[.006]



Pin Description								
2	4	5	10	13	14	15	16	7 12
RF In	-	-	RF Out	V_{DS}	V_{GS-m}	V_{DS}	V_{GS-d}	-
-	-	-	-	Main	Main	Drive	Drive	

^{*} Other Pins are GND.

Recommended Footprint & Coin Embedded



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ESD Sensitivity Ratings

	ESD Class	Standard
HBM	1A	ANSI/ESDA/JEDEC Standard JS-001
CDM	C1	ANSI/ESDA/JEDEC Standard JS-002

Packing Information

Part Number	Description
SDM23003-30H	600 pcs on a 13" reel (Standard)

Lot Number Description

2	4	0	9	0	1
1	2	3	4	5	6

①② Year Number

34 Week Number

56 Production Number

Revision History

GaN Hybrid PAM

SDM23003-30H



Part Number	Release Date	Version	Description	Data Sheet Status
SDM23003-30H	Feb, 2024	1.0	Initial Release	





Certification

This product is manufactured by a company that is certified for the AS9100D quality management system.

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